

Qualification Data for the 0.6um CMOS at Magnacip

QUALIFICATION RESULTS ADE7751/3/5/8			
TEST	CONDITIONS	SAMPLE SIZE (LOT/QTY)	RESULTS
Early Life Failure (ELF)	MIL-STD-883, Method 1015	2 x 800	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	2 x 417	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	2 x 627	Pass
High Temperature Operating Life (HTOL) <sup>#</sup>	JESD22-A108, 125°C<T <sub>j</sub> <135°C, Biased, 1,000 Hours	6 x 77	Pass
High Temperature Operating Life (HTOL)*	JESD22-A108, 125°C<T <sub>j</sub> <135°C, Biased, 1,000 Hours	3 x 77	In Process, expected completion Jan 2012
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	9 x 77	Pass
High Temperature Storage Life	JESD22-A103, 150°C, 1000hrs	3 x 45	Pass
High Temperature Storage Life	JESD22-A103, 150°C, 1000hrs	2 x 77	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101,	ADE7753	Pass 1250V
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101,	ADE7751 ADE7755 ADE7758	In Process, expected completion Jan 2012
Electrostatic Discharge (ESD) Human Body Model (HBM)	ANSI/ESDA/JEDEC JS-001- 2010	ADE7753	Pass 1500V
Electrostatic Discharge (ESD) Human Body Model (HBM)	ANSI/ESDA/JEDEC JS-001- 2010	ADE7751 ADE7755 ADE7758	In Process, expected completion Jan 2012
Latch-up	JEDEC JESD78	ADE7753	Pass
Latch-up	JEDEC JESD78	ADE7751 ADE7755 ADE7758	In Process, expected completion Jan 2012

\*Preconditioned per JEDEC/IPC J-STD-020 MSL 1

# Preconditioned per JEDEC/IPC J-STD-020 MSL 3